

## OptiMOS™-5 Power-Transistor





#### **Features**

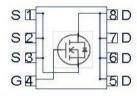
- N-channel Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green product (RoHS compliant)
- 100% Avalanche tested

#### **Product Summary**

$V_{\mathrm{DS}}$	80	V
R <sub>DS(on)</sub>	7.4	mΩ
$I_{D}$	70	Α



Туре	Package	Marking
IAUC70N08S5N074	PG-TDSON-8	5N08074



## **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T <sub>C</sub> =25°C, V <sub>GS</sub> =10V	70	А
		T <sub>C</sub> =100 °C, V <sub>GS</sub> =10 V <sup>1)</sup>	47	
Pulsed drain current <sup>1)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	280	
Avalanche energy, single pulse <sup>1)</sup>	E <sub>AS</sub>	/ <sub>D</sub> =35 A	57	mJ
Avalanche current, single pulse	IAS	-	70	А
Gate source voltage	$V_{GS}$	-	±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	83	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics <sup>1)</sup>						
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$	-	-	-	1.8	K/W

## **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### **Static characteristics**

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	80	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 36  \mu {\rm A}$	2.2	3	3.8	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS} = 80 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	0.1	1	μA
		$V_{\rm DS}$ =80 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =85 °C <sup>1)</sup>	1	1	20	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =6 V, I <sub>D</sub> =18 A	ı	9.1	10.6	mΩ
		V <sub>GS</sub> =10 V, I <sub>D</sub> =35 A		6.6	7.4	
Gate resistance <sup>1)</sup>	R <sub>G</sub>		-	1.2	-	Ω



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics <sup>1)</sup>						
Input capacitance	Ciss		-	1600	2080	pF
Output capacitance	Coss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, f=1 MHz	-	274	356	
Reverse transfer capacitance	C <sub>rss</sub>		-	14	22	
Turn-on delay time	t <sub>d(on)</sub>		-	4.7	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =40 V, V <sub>GS</sub> =10 V,	-	1.2	-	
Turn-off delay time	$t_{d(off)}$	$I_{D}$ =70 A, $R_{G}$ =3.5 Ω	-	7	-	
Fall time	$t_{\mathrm{f}}$	]	-	5.8	-	
Gate Charge Characteristics <sup>1)</sup> Gate to source charge	$Q_{\rm gs}$			8.0	10.0	nC
Gate to drain charge	Q <sub>gd</sub>	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =35 A, $V_{\rm GS}$ =0 to 10 V	_	5.2	8.0	-
Gate charge total	Q <sub>g</sub>		-	23.0	30.0	
Gate plateau voltage	V <sub>plateau</sub>		-	4.9	-	V
Reverse Diode						
Diode continous forward current <sup>1)</sup>	Is	T 25 °C	-	-	70	А
Diode pulse current <sup>1)</sup>	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	280	7
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =35 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time <sup>1)</sup>	t <sub>rr</sub>	V <sub>R</sub> =40 V, I <sub>F</sub> =50 A,	-	40	-	ns
	Q <sub>rr</sub>	$di_F/dt=100 \text{ A/µs}$		60		nC

 $<sup>^{\</sup>rm 1)}$  Defined by design. Not subject to production test.



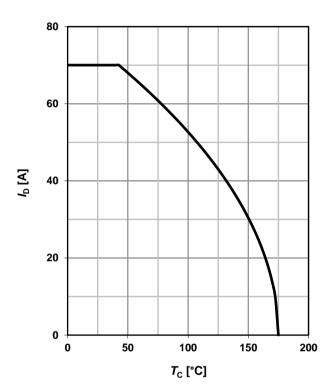
## 1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

# 100 80 60 40 20 0 50 100 150 200 T<sub>C</sub> [°C]

#### 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



## 3 Safe operating area

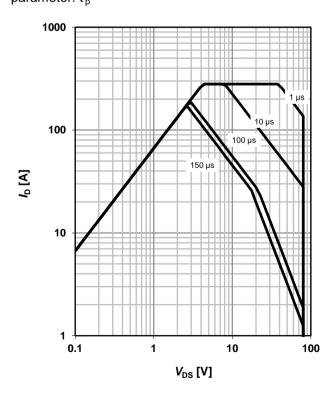
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

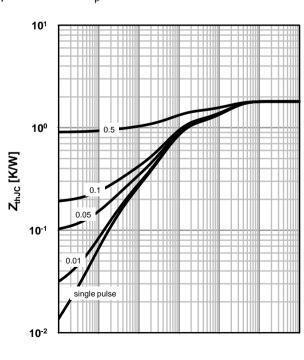
parameter:  $t_p$ 

## 4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_{p})$$

parameter:  $D=t_p/T$ 





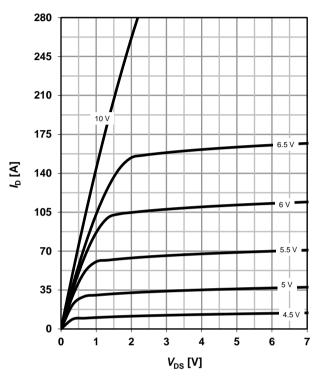
*t*<sub>p</sub> [s]



## 5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm i} = 25 \,{}^{\circ}{\rm C}$ 

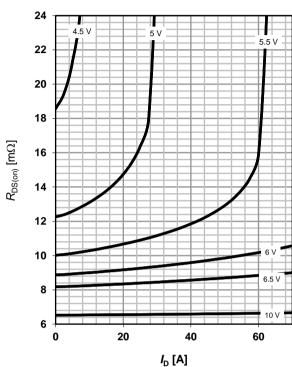
parameter: V<sub>GS</sub>



#### 6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ °C}$ 

parameter: V<sub>GS</sub>



## 7 Typ. transfer characteristics

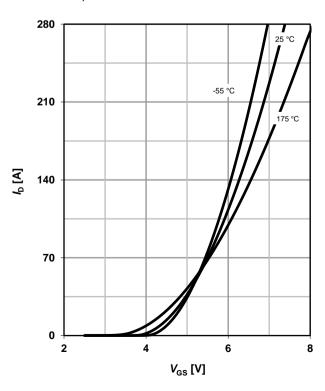
 $I_D = f(V_{GS}); V_{DS} = 6V$ 

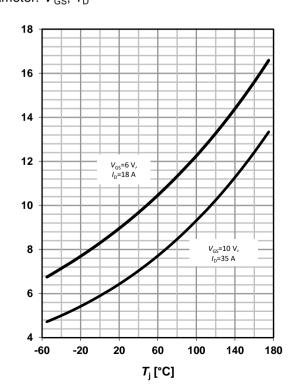
parameter:  $T_{\rm j}$ 

## 8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j)$ 

parameter:  $V_{GS}$ ;  $I_{D}$ 





 $R_{DS(on)}$  [m $\Omega$ ]



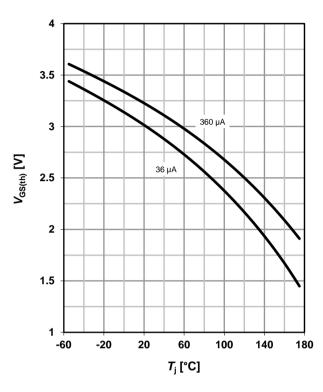
## 9 Typ. gate threshold voltage

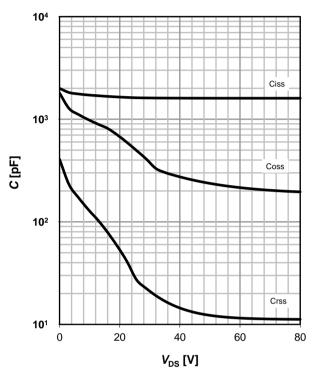
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>

## 10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 





## 11 Typical forward diode characteristicis

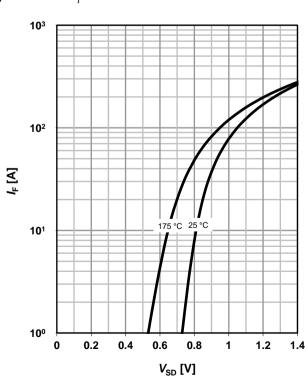
 $IF = f(V_{SD})$ 

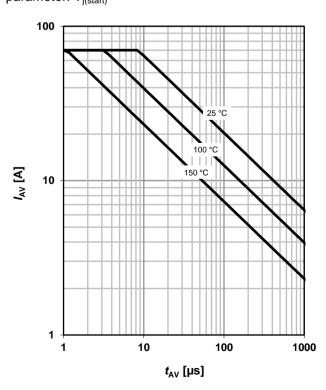
parameter:  $T_{\rm j}$ 

## 12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$ 

parameter: T<sub>j(start)</sub>







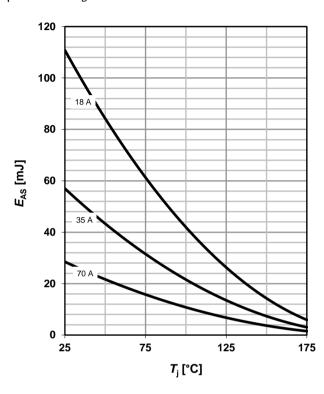
## 13 Typical avalanche energy

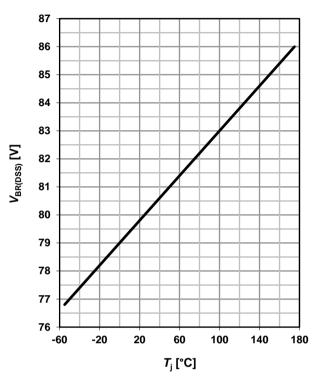
 $E_{AS} = f(T_i)$ 

parameter: I<sub>D</sub>

#### 14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_{D_{typ}} = 1 \text{ mA}$$

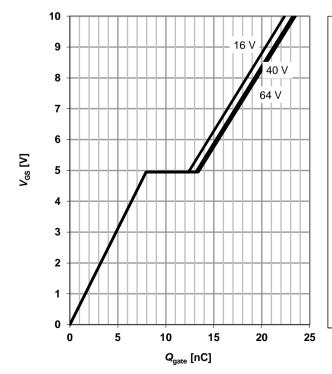




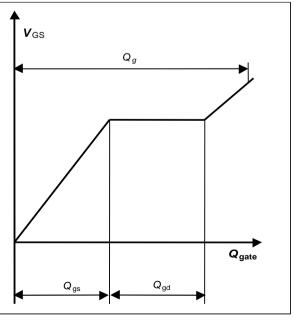
## 15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 35 A pulsed$ 

parameter: V<sub>DD</sub>



## 16 Gate charge waveforms





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**Revision History** 

Version	Date	Changes		
Version 1.0	24.07.2018	Final Data Sheet		